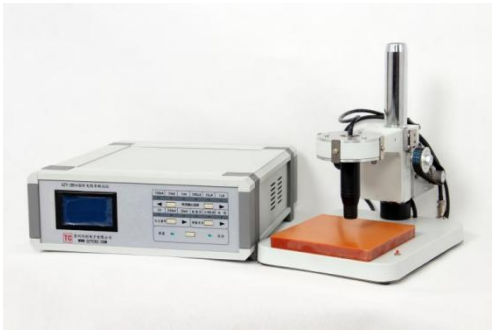
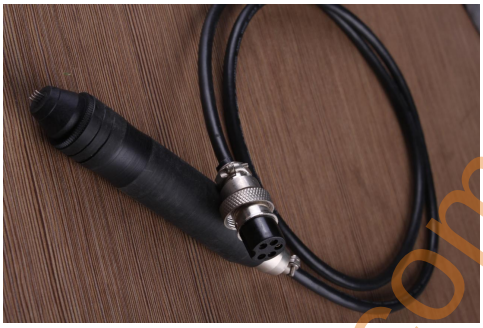
HangZhou Qiansineng Technology Co.,Ltd.

SZT-2B FOUR-POINT PROBE TESTER





1. The SZT-2B host utilizes advanced circuit design, resulting in faster and more accurate measurements. The LCD display provides clear readings, and the device comes with a computer interface and software for easy operation. The computer can automatically calculate, compare, and correct coefficients based on the specified thickness input, resulting in more precise measurements. Data can be easily stored or deleted for record-keeping purposes.
2. **The testing platform of the SZT-2B test fixture is 10 cm larger in length and width than traditional testing platforms**, making it suitable for larger-diameter materials. The test frame incorporates an automatic sensing device that decelerates when approaching the object to be measured, preventing the loss of the object and reducing probe wear. This feature improves measurement accuracy and is superior to similar products on the domestic market.
3. The instrument measures resistance, resistivity, and square resistance, and the standard coefficient is self-adjusting, eliminating the need for manual adjustment. The testing fixture pressure of this instrument can be adjusted in three levels. **The minimum resolution of the instrument is 0.1mΩ.**
4. The main machine is manual, while the test stand is automatic. The test probe is made of tungsten needle, which is superior to high-speed steel needles found in other probes on the market. Temperature compensation and voltage and current correction are automatically performed during each measurement.
5. **The whole machine measurement standard uncertainty is ≤ 2%**, which is significantly lower than the error rate of other domestic manufacturers (which is typically ≤ 5%).

-Technical parameters.

Measurement range		Constant current source	
Resistivity	10^{-4} ~ 10^{6}Ω-cm	Current output	DC 0~100mA continuously adjustable.
Square resistance	10^{-4} ~ 10^{6}Ω/□	Range	1,10, 100μA, 1, 10, 100mA
Resistance	10^{-4} ~ 10^{6}Ω	Error range	± 0.5% number ± 1
Measureable semiconductor material size		**Four-probe test probe**	
Diameter:	5mm-250mm	Probe spacing:	1mm
Length:	Any length is available (requires a manual probe)	Material:	Tungsten carbide.Probe mechanical wander rate: ±1.0%
Measurement method		**Display**	
Axial, cross-sectional can be		4 1/2, digital display, polarity, overload auto-show, Automatic display of decimal points and units	
Power supply	220±10% 50Hz or 60Hz Power consumption:< 35W		

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